

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Lancy Tsung

Docket No.: TI-30243

Serial No: TBD

Examiner: TBD

Filed: 08/02/01

Art Unit: TBD

For: MASS PRODUCTION OF CROSS-SECTION TEM SAMPLES BY
FOCUSED ION BEAM DEPOSITION AND ANISOTROPIC ETCHING

PRELIMINARY AMENDMENT

August 2, 2001

Assistant Commissioner for Patents

Washington, DC 20231

Dear Sir:

Please amend the above referenced application as follows:

In the Specification:

Page 1, before line 1, insert --This application claims priority under 35 USC §
119(e)(1) of provisional application numbers **60/222,462** filed **08/03/00**.--

REMARKS

Entry of the foregoing amendment prior to examination is respectfully requested.

If the Examiner has any questions or other correspondence regarding this application, Applicant requests that the Examiner contact Applicant's attorney at the below listed telephone number and address.

Respectfully submitted,



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